

42MX Family Devices Power-Up Behavior

Introduction

Actel antifuse FPGA families offer the advantage of nonvolatility by attaining immediate functionality at power up. Since the programmed design is retained, there is no requirement for additional configuration devices. This application note discusses the results of the 42MX device power-up characterization in detail and recommends appropriate power-up sequences and ramp rates. Tristate behavior of the device I/Os during the power-up cycle offers the flexibility of applying voltages to the I/Os during power-up.

The characterization measurement was carried out in a laboratory environment and the reported data are typical. Hence, the maximum and minimum values under worst and best condition are not guaranteed.

Background

For 42MX devices manufactured before April 1999, the I/Os would go incorrectly into tristate mode under certain power-up conditions. In an effort to resolve this problem, Actel has created an updated set of 42MX devices, designated by "X39" in their part number. For more information, please refer to the following GURU documents:

http://www.actel.com/apps/guru/apr99/ns845.html http://www.actel.com/apps/guru/jul99/ns842.html

This application note includes the characterization reports for both old and new versions of the 42MX family and is a general source for all 42MX devices.

All 42MX devices have two power supplies: V_{CCA} and $V_{CCI},$ and they can operate in 5V only, 3.3V only, and 5V/3.3V mixed systems. Table 1 summarizes the voltage levels of these power supplies and the corresponding I/O voltage level.

 Table 1
 Power Supply Levels for Different Operations

V _{CCA}	V _{CCI}	Input	Output
5V	5V	5V	5V
3.3V	3.3V	3.3V	3.3V
5V	3.3V	3.3V, 5V	3.3V

As seen from Table 1, V_{CCA} also acts as an input tolerance voltage while V_{CCI} is used as an I/O module voltage. In single voltage operations, V_{CCA} and V_{CCI} are usually tied to each other but for the mixed 5V/3.3V systems (V_{CCA} =5V and V_{CCI} =3.3V), V_{CCA} must be greater than or equal to V_{CCI} throughout the power-up sequence. Hence, V_{CCA} must always be powered up before V_{CCI} to avoid excessive currents and/or damage to the device.

If V_{CCI} is 0.5V greater than V_{CCA} when both are above 1.5V, then the input protection junction on the I/Os will be forward biased, causing them to draw large amounts of current. When V_{CCA} and V_{CCI} are in the 1.5V to 2.0V region and V_{CCI} is greater than V_{CCA} , all I/Os would momentarily behave as outputs that are in a logical high state, and I_{CC} rises to high levels.

Transient Current

Due to the internal logic switching simultaneously during the power-up sequence, a relatively large transient current appears on the I/Os. The amount and duration of this transient current is critical for protecting the board from any possible damages. The transient current is dependent on the $V_{\rm CCA}$ voltage level (3.3V or 5V) and its ramp rate during power-up. Since the transient current is not due to I/O switching, its value and duration is independent of the $V_{\rm CCL}$ level.

Transient current measurements are taken for three different operating conditions:

- 5V only: $V_{CCA}=V_{CCI}=5V$
- 3.3V only: V_{CCA}=V_{CCI}=3.3V
- Mixed 5V/3.3V: V_{CCA}=5V (powered up first), V_{CCI}=3.3V (powered up second)

Different ramp rates have been applied to the power supplies. Additionally, in the mixed voltage operation condition, different delays between V_{CCA} and V_{CCI} have been tested ranging from 100µs to 250ms. Table 2 and Table 3 on page 2 indicate the amount of the transient current peak in single voltage operation conditions for X39 and non-X39 series, respectively.

It can be derived from the measured data that, the average pulse width of the transient current spike is 350ns with its value increasing as the power supply ramp rate increases. The transient current peak value is also related to the number of logic modules in the device, meaning that larger



devices show a higher transient current. For instance, for all of the X39 series tested devices, 42MX36 has a higher transient current than 42MX24, which in turn, has a higher transient current than 42MX16. However, for the non-X39 measured devices, some discrepancies can be observed. These discrepancies can be seen in Table 2 and Table 3. The transient currents were reduced with the slower ramp rates. Figure 1 shows the relation between the ramp rates and the transient current peak for the X39 series of 42MX family devices.

For mixed voltage systems, the transient current is very similar to that of the 5V only operation.

		Transient Current on V _{CCA} (mA) at different ramp rates (avg. values)							
Operating Systems	Products	0.5V/ms	0.05V/ms	10V/ms	5V/ms	0.5V/ms	0.2V/ms	0.05V/ms	
	42MX16 X39	428	319	255	165	101	95	92	
	42MX24 X39	490	465	340	250	130	108	110	
5V-only systems	42MX36 X39	539	531	357	346	151	117	112	
		Transient Current on V _{CCA} (mA) at different ramp rates (avg. values)							
	Products	0.33V/ms	0.033V/ms	6.6V/ms	3.3V/ms	0.33V/ms	0.132V/ms	0.033V/ms	
3.3V-only systems	42MX16 X39	196	189	183	148	97	95	90	
	42MX24 X39	281	276	265	216	129	113	107	
	42MX36 X39	324	327	321	284	124	112	110	

 Table 2
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 Transient Current for X39 42MX Parts at Different Ramp Rates
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Table 3 • T	Fransient Current for	Non-X39 42MX Parts a	t Different Ramp Rates
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		Transient Current on V _{CCA} (mA) at different ramp rates (avg. values)								
Operating Systems	Products	0.5V/ms	0.05V/ms	10V/ms	5V/ms	0.5V/ms	0.2V/ms	0.05V/ms		
	42MX16	N/A	N/A	189	140	47	45	43		
5V-only systems	42MX24	N/A	N/A	250	234	202	200	197		
	42MX36	N/A	N/A	78	64	56	117	108		
Transient Current on V _{CCA} (mA) at different ramp rates (av							tes (avg. val	ues)		
	Products	0.33V/ms	0.033V/ms	6.6V/ms	3.3V/ms	0.33V/ms	0.132V/ms	0.033V/ms		
3.3V-only systems	42MX16	184	171	150	114	50	49	85		
	42MX24	225	220	208	207	205	199	197		
	42MX36	159	89	70	65	55	114	112		



Figure 1 • Transient Current vs. Ramp Rates for MX16, MX24, and MX36 at 5V and 3.3V Operating Conditions

I/O Behavior During Power Up

This section discusses the behavior of 42MX device family I/Os during power-up cycles. One of the important parameters during power up is the voltage level at which the I/Os become functional. Since the functionality of I/Os is defined by the time the internal logic is functional, the power up to functional time depends on the ramp rates of $V_{\rm CCA}$ and not $V_{\rm CCI}$. However, the proper data cannot be read from or written into the device unless $V_{\rm CCI}$ reaches the

value where I/Os become active. After the I/Os become active, there will be some additional delay for the input data to propagate to the output pins. In single-voltage operations, there is only one power supply. Therefore, the power up to functional times and I/O functional times are equal. Table 4 and Table 5 present the power up to functional voltage levels for the single-voltage operation mode.

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Ramp Rate	0.5V/ms	0.05V/ms	10V/ms	5V/ms	0.5V/ms	0.2V/ms	0.05V/ms
42MX16 X39	5.00	4.65	3.13	2.81	2.41	2.31	2.25
42MX24 X39	5.00	4.81	3.63	3.16	2.41	2.40	2.34
42MX36 X39	5.00	4.91	3.92	3.73	2.54	2.38	2.36
42MX16	N/A	N/A	3.51	2.87	1.90	1.77	1.73
42MX24	N/A	N/A	3.53	3.00	2.55	2.50	2.49
42MX36	N/A	N/A	1.96	1.94	1.86	2.41	2.38

Table 4 • V_{CCA} Voltage where I/Os become Active in 5V-only Operation (V)

Ramp Rate	0.33V/ms	0.033V/ms	6.6V/ms	3.3V/ms	0.33V/ms	0.132V/ms	0.033V/ms	
42MX16 X39	3.30	3.30	2.88	2.66	2.33	2.30	2.25	
42MX24 X39	3.30	3.30	3.19	2.93	2.40	2.34	2.28	
42MX36 X39	3.30	3.30	3.30	3.07	2.46	2.41	2.34	
42MX16	3.30	3.30	3.01	3.67	1.78	1.76	1.65	
42MX24	3.30	3.30	3.11	2.70	2.47	2.43	2.43	

1.91

2.07

 Table 5
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 V_{CCA} Voltage where I/Os become Active in 3.3V-only Operation (V)

2.53

Table 4 and Table 5 indicate that the power up to functional voltage level increases for faster ramp rates and larger arrays.

42MX36

Generally, in a mixed-voltage operation mode, since the array voltage (V_{CCA}) is 5V and, as discussed earlier, the power up to functional time depends on the V_{CCA} ramp-up, Table 4 applies for mixed-voltage mode. However, there are two cases that should be taken into consideration during the power up in a mixed-voltage mode. The first case occurs when the power-up delay between V_{CCA} and V_{CCI} is larger than the power-up to functional time. In this case, the internal modules are functional and I/Os are inactive. Therefore, the I/Os' functional time will be defined as the time when V_{CCI} is powered up. The second case is more critical and happens if the power-up delay between V_{CCA} and V_{CCI} is less than the power up to functional time. In other words, it happens when the I/Os are functional but the internal logic modules are not. Thus, the I/Os will be driven to their designated voltage level as soon as the power-up to functional time is reached. In such a condition, there is a short period of time (after I/O activation and before array functionality) that the I/Os might be driven into an unknown state. Hence, it is recommended to power up V_{CCI} after V_{CCA} has reached its functional level.

During the characterization procedure, the inputs and outputs of 42MX family devices are tested to determine their behavior during power up, specifically before they become functional. The results of different measurements demonstrate that the I/Os are tristated during the power-up. In other words, a voltage can be applied to a 42MX device I/O before and during power up of the device.

2.38

2.38

1.79

Users should note that for non-X39 devices in 5V-only operation, if the power-up ramp rate of V_{CCI} is faster than 0.01V/ms, the I/Os will be driven into an unknown tristate mode, and the device will not function properly.

Conclusion

1.82

For proper power up of 42MX family devices, V_{CCA} should always be greater than V_{CCI} during power up. In older generations (non-X39) of the 42MX family, there is a power-up rise time restriction to avoid an incorrect tristate on I/Os. This document discussed the transient current on V_{CCA} and functional voltage level during power-up. The transient current in 42MX devices is reduced by increasing the power-up rise time. For the faster power ups, the voltage level in which the device becomes functional is higher. 42MX device I/Os are also tristated before reaching the functionality point, which makes it possible to apply voltage on I/Os during power up.

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